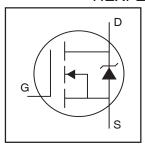
International Rectifier

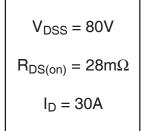
IRLR2908PbFIRLU2908PbF

HEXFET® Power MOSFET

Features

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Timax
- Lead-Free

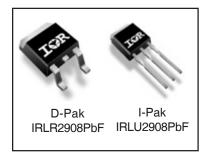




Description

This HEXFET ® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this HEXFET power MOSFET are a 175°C junction operating temperature, low RθJC, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

The D-Pak is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	39	Α
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (See Fig. 9)	28	*
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	30	*
I _{DM}	Pulsed Drain Current ①	150	*
P _D @T _C = 25°C	Maximum Power Dissipation	120	W
	Linear Derating Factor	0.77	W/°C
V_{GS}	Gate-to-Source Voltage	± 16	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	180	mJ
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value ②	250	•
I _{AR}	Avalanche Current ①	See Fig.12a,12b,15,16	Α
E _{AR}	Repetitive Avalanche Energy ®		mJ
dv/dt	Peak Diode Recovery dv/dt ③	2.3	V/ns
T_J	Operating Junction and	-55 to + 175	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.3	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ®		40	
$R_{\theta JA}$	Junction-to-Ambient		110	

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Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	80			٧	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.085		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		22.5	28	mΩ	V _{GS} = 10V, I _D = 23A ④
			25	30	1	V _{GS} = 4.5V, I _D = 20A ④
V _{GS(th)}	Gate Threshold Voltage	1.0		2.5	٧	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
gfs	Forward Transconductance	35			S	$V_{DS} = 25V, I_{D} = 23A$
I _{DSS}	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 80V, V_{GS} = 0V$
				250	1	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			200	nA	V _{GS} = 16V
	Gate-to-Source Reverse Leakage			-200	1	V _{GS} = -16V
Q_g	Total Gate Charge		22	33	nC	I _D = 23A
Q _{gs}	Gate-to-Source Charge		6.0	9.1	Ī	$V_{DS} = 64V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		11	17	Ī	$V_{GS} = 4.5V$
t _{d(on)}	Turn-On Delay Time		12		ns	$V_{DD} = 40V$
t _r	Rise Time		95		Ī	$I_D = 23A$
t _{d(off)}	Turn-Off Delay Time		36		Ī	$R_G = 8.3\Omega$
t _f	Fall Time		55		Ī	V _{GS} = 4.5V ④
L _D	Internal Drain Inductance		4.5		nH	Between lead,
						6mm (0.25in.)
L _S	Internal Source Inductance		7.5		Ī	from package
						and center of die contact
C _{iss}	Input Capacitance		1890		pF	$V_{GS} = 0V$
Coss	Output Capacitance		260		Ī	$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		35		Ī	f = 1.0MHz, See Fig. 5
C _{oss}	Output Capacitance		1920		ĺ	$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
C _{oss}	Output Capacitance		170		Ī	$V_{GS} = 0V, V_{DS} = 64V, f = 1.0MHz$
C _{oss} eff.	Effective Output Capacitance		310		ĺ	$V_{GS} = 0V$, $V_{DS} = 0V$ to 64V

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			39		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			150		integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 23A$, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		75	110	ns	$T_J = 25^{\circ}C, I_F = 23A, V_{DD} = 25V$
Q _{rr}	Reverse Recovery Charge		210	310	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsio	turn-or	time is	negligib	le (turn-on is dominated by LS+LD)

Notes ① through ® are on page 11

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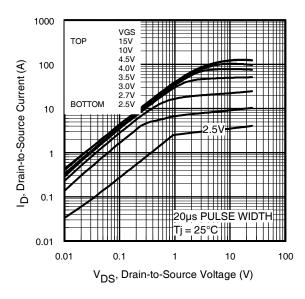


Fig 1. Typical Output Characteristics

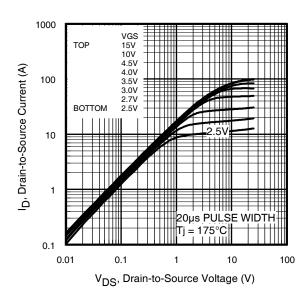


Fig 2. Typical Output Characteristics

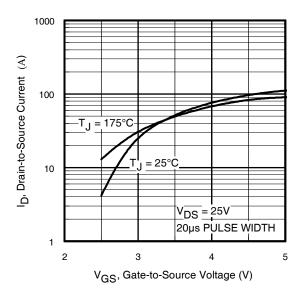


Fig 3. Typical Transfer Characteristics

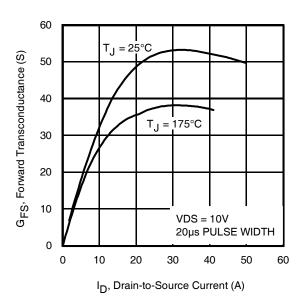


Fig 4. Typical Forward Transconductance vs. Drain Current

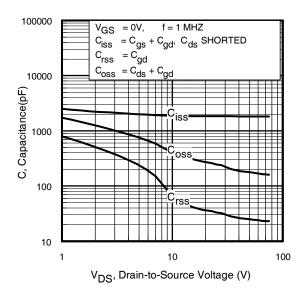


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

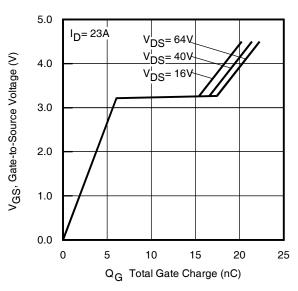


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

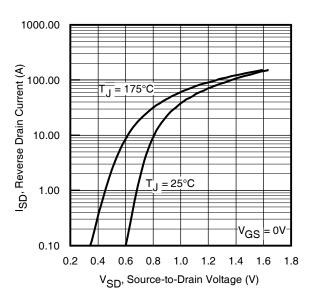


Fig 7. Typical Source-Drain Diode Forward Voltage

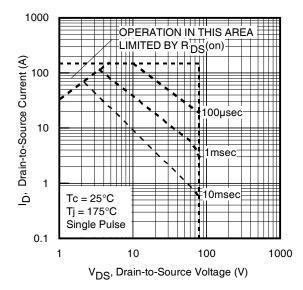


Fig 8. Maximum Safe Operating Area

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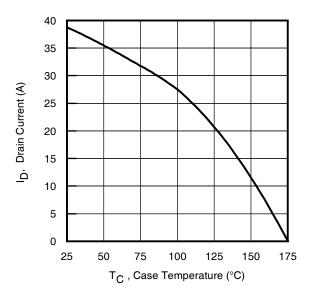


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Normalized On-Resistance vs. Temperature

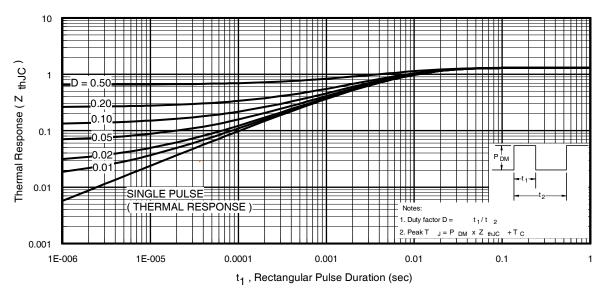


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

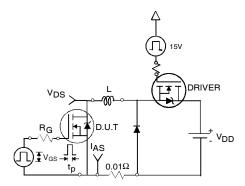


Fig 12a. Unclamped Inductive Test Circuit

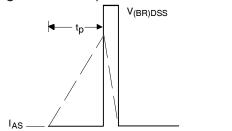


Fig 12b. | Unclamped Inductive Waveforms

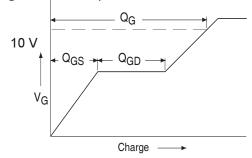


Fig 13a. Basic Gate Charge Waveform

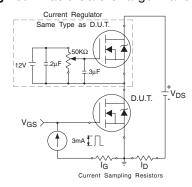


Fig 13b. Gate Charge Test Circuit 6

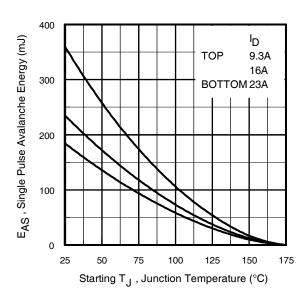


Fig 12c. Maximum Avalanche Energy vs. Drain Current

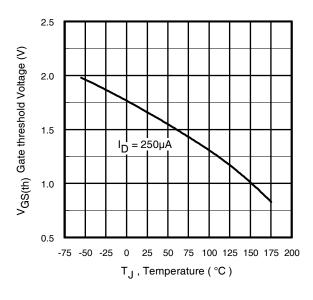


Fig 14. Threshold Voltage vs. Temperature www.irf.com

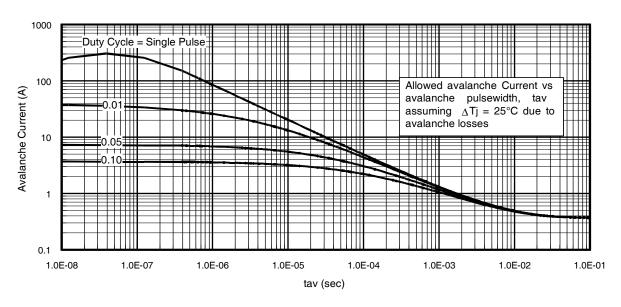


Fig 15. Typical Avalanche Current vs. Pulsewidth

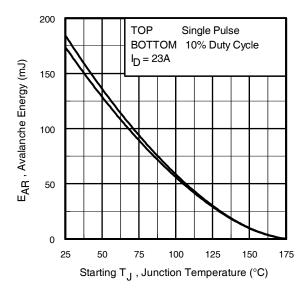


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{imax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. P_{D (ave)} = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{imax} (assumed as 25°C in Figure 15, 16). t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ (} 1.3 \cdot \text{BV} \cdot I_{av} \text{)} = \triangle \text{T} / Z_{thJC} \\ I_{av} &= 2\triangle \text{T} / \left[1.3 \cdot \text{BV} \cdot Z_{th} \right] \\ E_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$

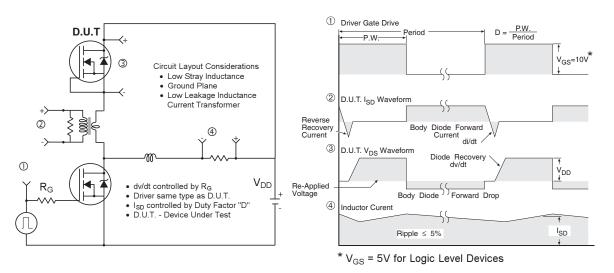


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

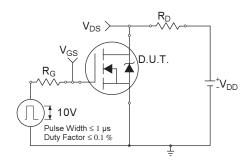


Fig 18a. Switching Time Test Circuit

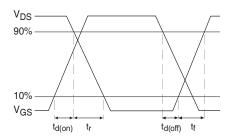


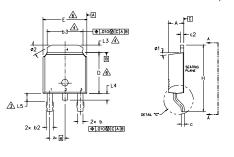
Fig 18b. Switching Time Waveforms

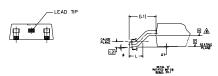
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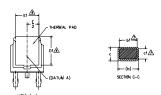
IRLR/U2908PbF

D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)







- NOTES:

 1.— DIMENSIONING AND TOLERANCING PER ASME Y14.5M—1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- A- DIMENSION D1, E1, L3 & 63 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.

 A- DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S Y M		DIMEN	SIONS		Ŋ
B O	MILLIM	ETERS	INCHES		O T
L	MIN.	MAX,	MIN.	MAX.	E S
Α	2,18	2.39	.086	.094	
A1	-	0.13	-	,005	
ь	0.64	0.89	.025	.035	
ь1	0.65	0.79	.025	.031	7
b2	0.76	1,14	.030	.045	
b3	4,95	5.46	.195	.215	4
c	0.46	0.61	.018	.024	
c1	0.41	0.56	.016	.022	7
c2	0.46	0.89	.018	.035	
D	5,97	6.22	.235	.245	6
D1	5.21	-	.205	-	4
Ε	6.35	6.73	.250	.265	6
E1	4.32	-	.170	-	4
е	2.29	BSC	.090	BSC	
Н	9.40	10,41	.370	,410	
L	1,40	1,78	.055	,070	
L1	2.74	BSC	.108	REF.	
L2	0.51	BSC	.020	BSC	
L3	0,89	1,27	.035	,050	4
L4	-	1,02	-	.040	
L5	1,14	1.52	.045	.060	3
ø	0.	10*	0*	10"	
ø1	0.	15*	0,	15*	
Ф2	25*	35*	25*	35*	

LEAD ASSIGNMENTS

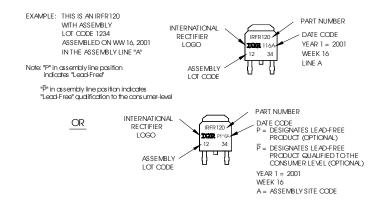
<u>HEXFET</u>

- 1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

IGBT & CoPAK

- 1.- GATE
 2.- COLLECTOR
 3.- EMITTER
 4.- COLLECTOR

D-Pak (TO-252AA) Part Marking Information



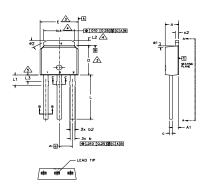
- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

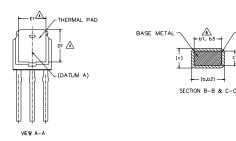
IRLR/U2908PbF



I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)





NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- ⚠ DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
- A- LEAD DIMENSION UNCONTROLLED IN L3.
- A- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.
- 7.- DUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA (Date 06/02).
- 8.- CONTROLLING DIMENSION : INCHES.

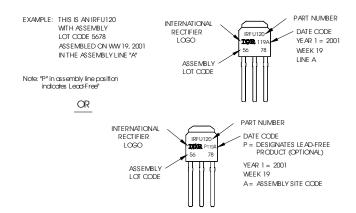
S	S Y DIMENSIONS				
B 0	MILLIM	ETERS	INCHES		N O T E S
L	MIN.	MAX.	MIN.	MAX.	S
Α	2,18	2.39	.086	.094	
A1	0.89	1,14	.035	.045	
b	0.64	0.89	.025	.035	
b1	0,65	0.79	.025	,031	6
b2	0.76	1,14	.030	.045	
ь3	0,76	1,04	.030	,041	6
b4	4,95	5,46	.195	.215	4
С	0.46	0.61	.018	.024	
c1	0,41	0.56	.016	.022	6
c2	0,46	0.89	,018	.035	
D	5.97	6.22	.235	.245	3
D1	5.21	-	.205	-	4
Ε	6,35	6.73	.250	.265	3
E1	4,32	-	,170	-	4
е	2,29	2,29 BSC		.090 BSC	
L	8.89	9.65	.350	.380	
L1	1,91	2.29	.045	.090	
L2	0,89	1.27	.035	.050	4
L3	1,14	1.52	.045	,060	5
ø1	0,	15"	0+	15*	
ø2	25*	35*	25*	35*	

LEAD ASSIGNMENTS

HEXFET

1.- GATE
2.- DRAIN
3.- SOURCE
4.- DRAIN

I-Pak (TO-251AA) Part Marking Information



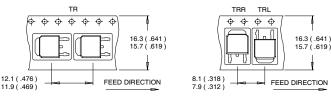
Notes:

- 1. For an Automotive Qualified version of this part please see http://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

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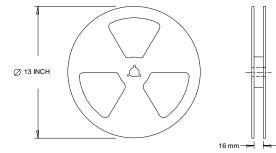
D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)



NOTES

- 1. CONTROLLING DIMENSION: MILLIMETER.
 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES : 1. OUTLINE CONFORMS TO EIA-481.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by T_{Jmax} , starting $T_{J} = 25^{\circ}C$, L = 0.71mH, $R_{G} = 25\Omega$, $I_{AS} = 23A$, $V_{GS} = 10V$. Part not recommended for use above
- $\exists \quad I_{SD} \leq 23A, \ di/dt \leq 400A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_{J} \leq 175^{\circ}C.$
- 4 Pulse width \leq 1.0ms; duty cycle \leq 2%.
- \odot C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- 6 Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- This value determined from sample failure population. 100% tested to this value in production.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information. 10/2010

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